



General Description

The HXYG80P06T use advanced SGT MOSFET technology to provide low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. This device is specially designed to get better ruggedness and suitable.

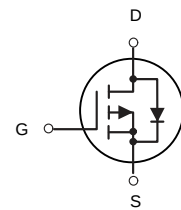
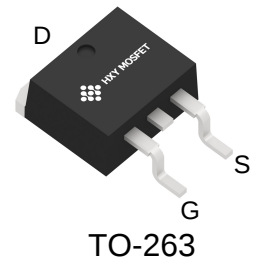
General Features

$V_{DS} = -60V$ $I_D = -80A$

$R_{DS(ON)} < 11m\Omega$ @ $V_{GS} = -10V$

Applications

Consumer electronic power supply Motor control
Synchronous-rectification Isolated DC
Synchronous-rectification applications



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
HXYG80P06T	TO-263	HXY MOSFET	800

Absolute Maximum Ratings at $T_J = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	V_{DS}	-60	V
Gate source voltage	V_{GS}	± 20	V
Continuous drain current ¹⁾	I_D	-80	A
Pulsed drain current ²⁾	$I_{D, pulse}$	-320	A
Power dissipation ³⁾	P_D	110	W
Single pulsed avalanche energy ⁵⁾	EAS	450	mJ
Operation and storage temperature	T_{stg}, T_J	-55 to 150	$^\circ C$
Thermal resistance, junction-case	$R_{\theta JC}$	1.1	$^\circ C/W$



Static Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-60	--	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} = -60V, V _{GS} = 0V	--	--	1	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =-20V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =+20V	--	--	-100	nA
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-1.3	-1.8	-2.3	V
R _{DS(ON)1}	Drain-to-Source On-Resistance	V _{GS} =-10V, I _D =-20A	--	9.0	11.0	mΩ
R _{DS(ON)2}	Drain-to-Source On-Resistance	V _{GS} =-4.5V, I _D =-15A	--	12.0	16.0	mΩ
g _{FS}	Forward Transconductance	V _{DS} =-5V, I _D =-20A	50	--	--	S

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
C _{iss}	Input Capacitance	V _{GS} =0V	--	3060	--	pF
C _{oss}	Output Capacitance	V _{DS} =-30V	--	620	--	
C _{rss}	Reverse Transfer Capacitance	f=1.0MHz	--	20	--	
R _g	Gate resistance	V _{GS} =0V, V _{DS} Open	--	2.0	--	Ω

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D =-20A, R _L =0.75Ω	--	4.5	--	ns
t _r	Rise Time	V _{DS} = -30V	--	2.5	--	
t _{d(OFF)}	Turn-Off Delay Time	V _{GS} = -10V	--	14.5	--	
t _f	Fall Time	R _G = 3Ω	--	3.5	--	
Q _g	Total Gate Charge	V _{GS} =-10V	--	56	--	nC
Q _{gs}	Gate Source Charge	V _{DS} =-30V	--	11	--	
Q _{gd}	Gate Drain Charge	I _D =-20A	--	9	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
I _S	Diode Forward Current	T _C =25 °C	--	--	-80	A
I _{SM}	Diode Pulse Current		--	--	-320	A
V _{SD}	Diode Forward Voltage	I _S =-6.0A, V _{GS} =0V	--	--	-1.2	V
t _{rr}	Reverse Recovery time	I _S =-20A, V _{DD} =-30V	--	60	--	ns
Q _{rr}	Reverse Recovery Charge	dI/dt=100A/μs	--	105	--	nC

a1: Repetitive rating; pulse width limited by maximum junction temperature

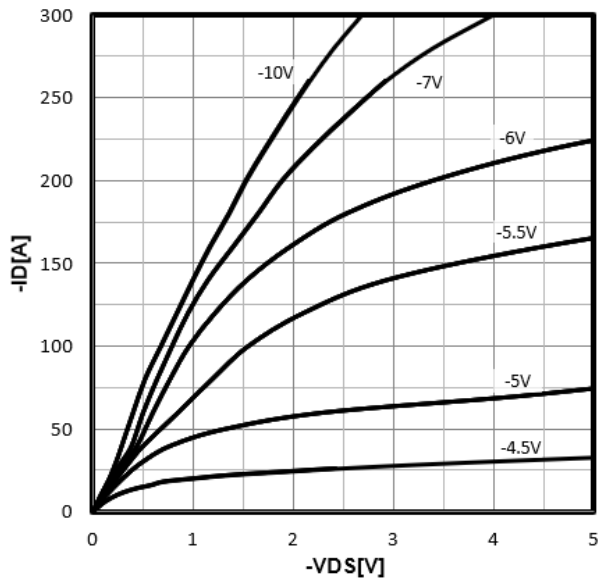
a2: V_{DD} =30V, L=0.3mH, R_G =25Ω, Starting T_J=25°C



Characteristics Curve

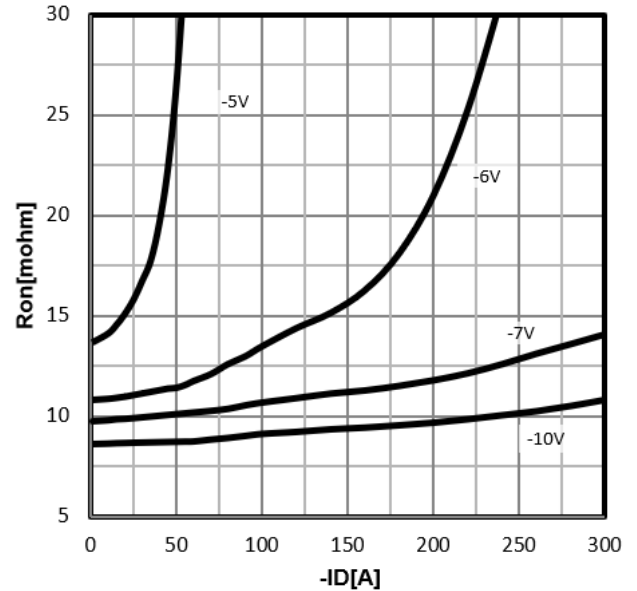
Typ. output characteristics

$$I_D = f(V_{DS})$$



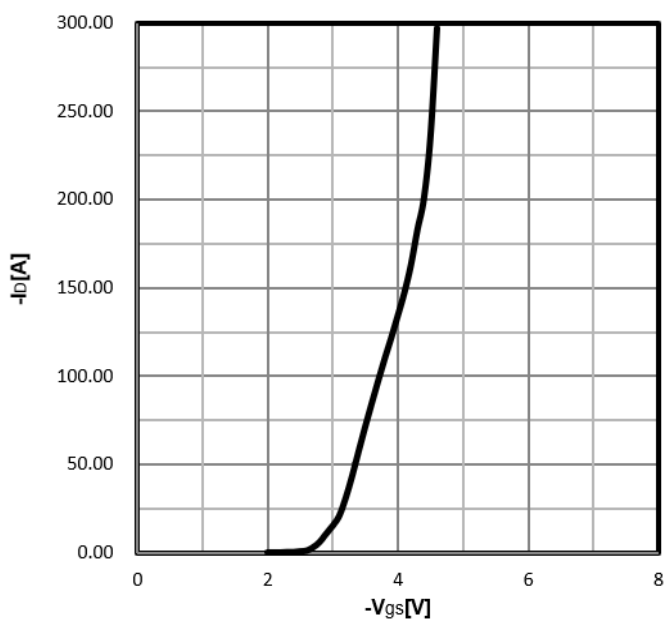
Typ. drain-source on resistance

$$R_{DS(on)} = f(I_D)$$



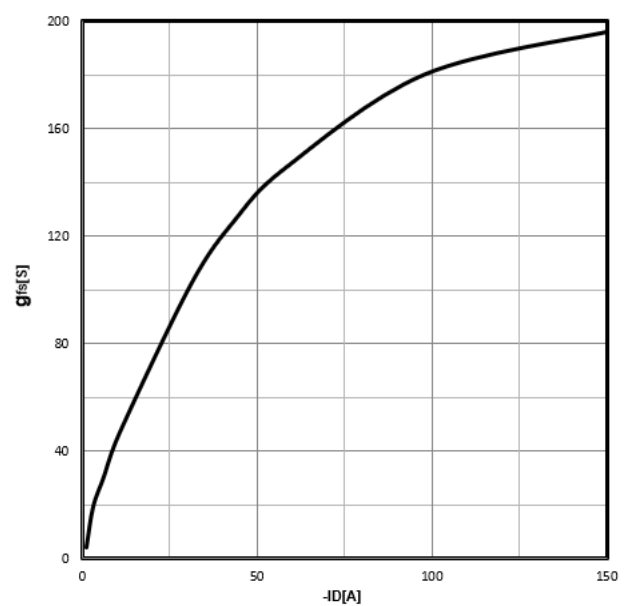
Typ. transfer characteristics

$$I_D = f(V_{GS})$$



Typ. forward transconductance

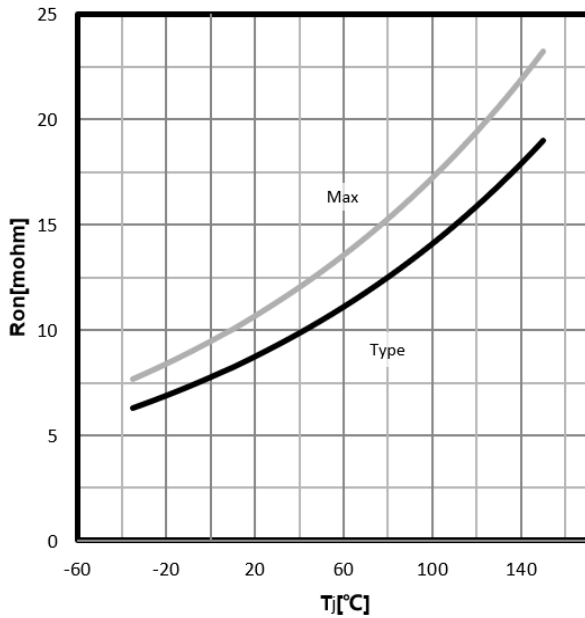
$$g_{fs} = f(I_D)$$





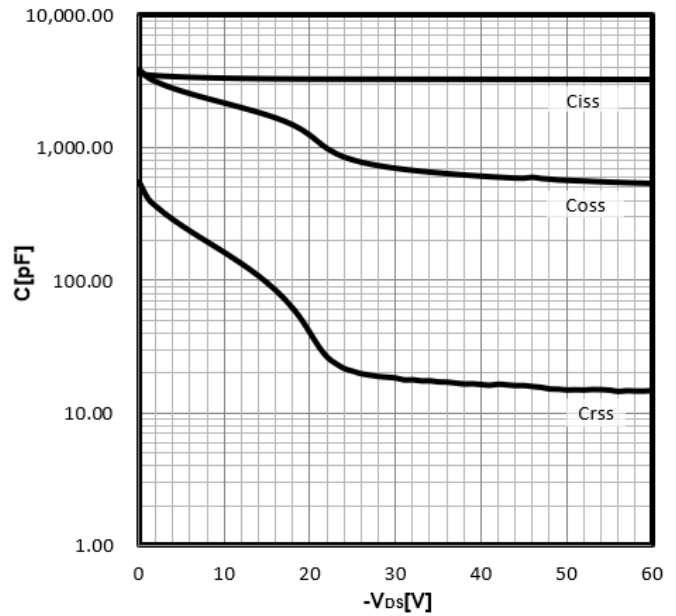
Drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = -20A; V_{GS} = -10V$$



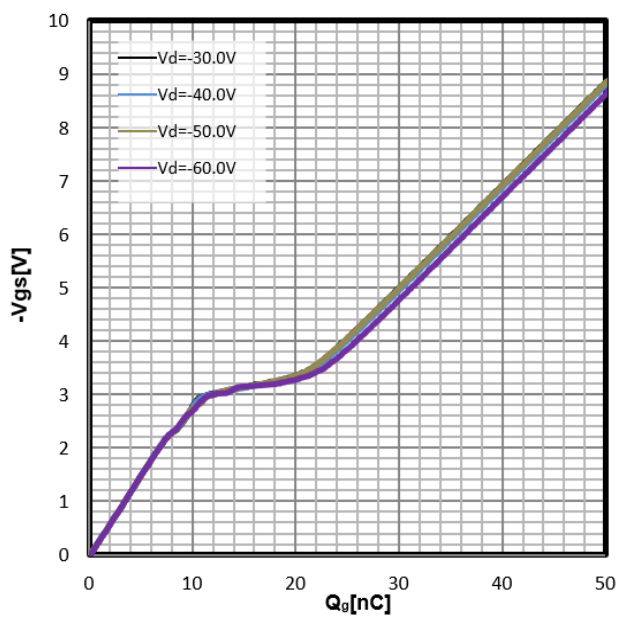
Typ. capacitances

$$C = f(V_{DS}); V_{GS} = 0V; f = 1MHz$$



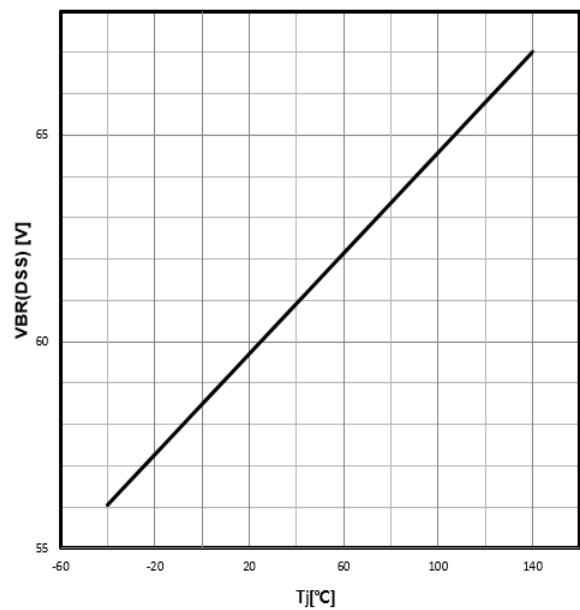
Typ. gate charge

$$V_{GS} = f(Q_{gate}); I_D = -20A$$



Drain-source breakdown voltage

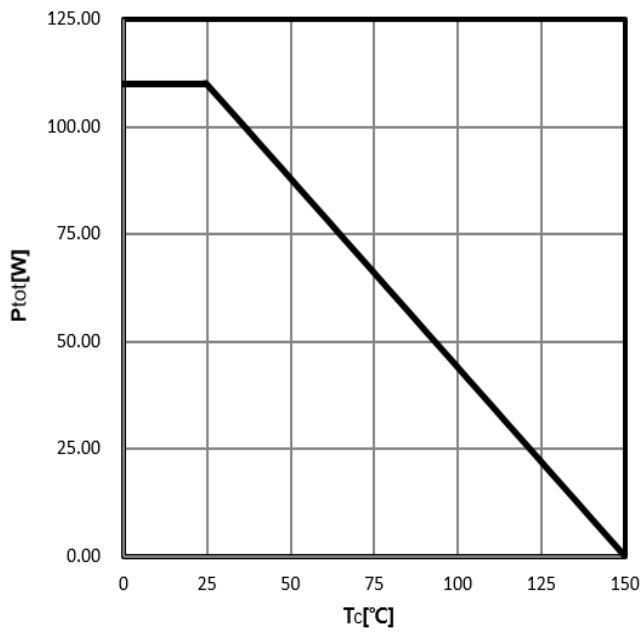
$$V_{BR(DSS)} = f(T_j); I_D = -250\mu A$$



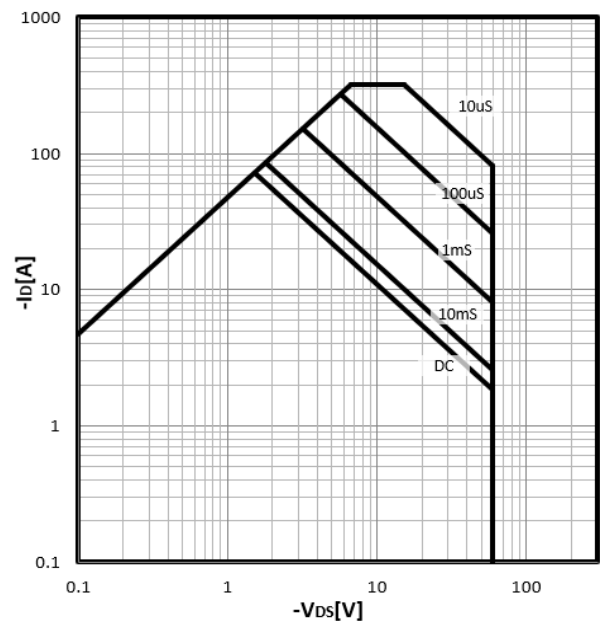


Power Dissipation

$$P_{tot}=f(T_c)$$

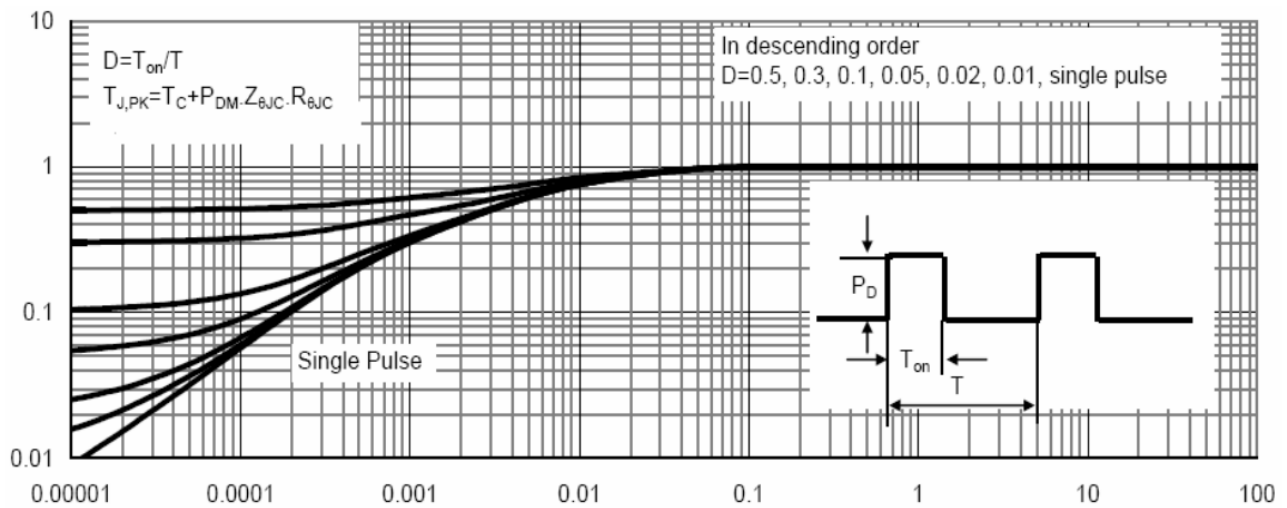


$$I_D=f(V_{DS})$$



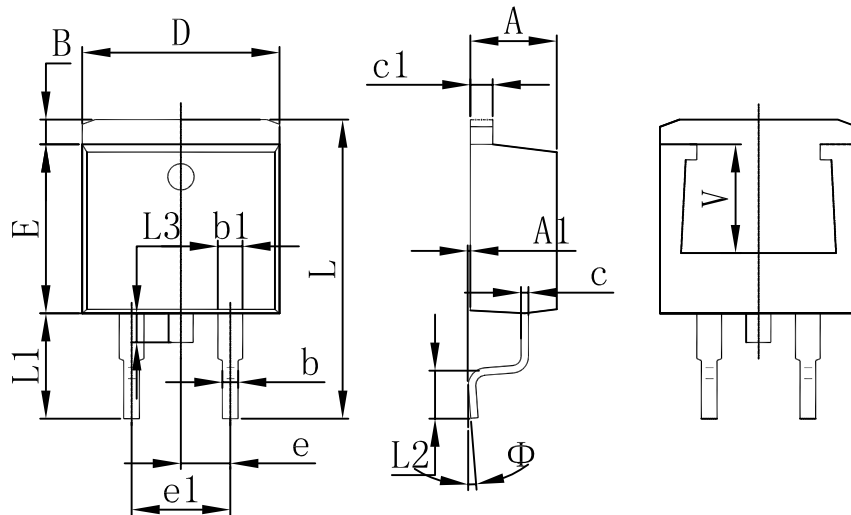
Max. transient thermal impedance

$$Z_{thJC}=f(t_p)$$





TO-263 Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.470	4.670	0.176	0.184
A1	0.000	0.150	0.000	0.006
B	1.120	1.420	0.044	0.056
b	0.710	0.910	0.028	0.036
b1	1.170	1.370	0.046	0.054
c	0.310	0.530	0.012	0.021
c1	1.170	1.370	0.046	0.054
D	10.010	10.310	0.394	0.406
E	8.500	8.900	0.335	0.350
e	2.540 TYP.		0.100 TYP.	
e1	4.980	5.180	0.196	0.204
L	14.940	15.500	0.588	0.610
L1	4.950	5.450	0.195	0.215
L2	2.340	2.740	0.092	0.108
L3	1.300	1.700	0.051	0.067
Φ	0°	8°	0°	8°
V	5.600 REF.		0.220REF.	



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